

Notice of References Cited	Application/Control No. 10/716,913		Applicant(s)/Patent Under Reexamination FLETCHER ET AL.	
	Examiner Jack W. Szeto		Art Unit 2113	Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,239,646 A	08-1993	Kimura, Makoto	714/54
*	B	US-5,608,878 A	03-1997	Arimilli et al.	710/107
*	C	US-5,724,609 A	03-1998	Hatae et al.	710/22
*	D	US-5,764,929 A	06-1998	Kelley et al.	710/107
*	E	US-5,978,937 A	11-1999	Miyamori et al.	714/45
*	F	US-5,991,900 A	11-1999	Garnett, Paul J.	714/56
*	G	US-6,145,044 A	11-2000	Ogura, Shiro	710/311
*	H	US-6,173,351 B1	01-2001	Garnett et al.	710/309
*	I	US-6,223,230 B1	04-2001	Garnett et al.	710/26
*	J	US-6,240,476 B1	05-2001	Garcia et al.	710/107
*	K	US-6,438,639 B1	08-2002	Bakke et al.	710/302
*	L	US-2003/0093746 A1	05-2003	Kang et al.	714/774
*	M	US-2006/0085692 A1	04-2006	Berbaum et al.	714/043

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Wuudiann Ke, Duy Le, Najmi T. Jarwala: A Secure Data Transmission Scheme for 1149.1 Backplane Test Bus. ITC 1995: 789-796			
	V	Chan, S.; Huy Luong; Charlan, W.; Fukuhara, R.; Homberg, E.; Jones, P.; Pixler, G.: The implementation of a COTS based fault tolerant avionics bus architecture. 2000. Page(s): 297-305 vol.7			
	W				
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/716,913	Applicant(s)/Patent Under Reexamination FLETCHER ET AL.	
	Examiner Jack W. Szeto	Art Unit 2113	Page 2 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,843,544 A	06-1989	DuLac et al.	710/53
*	B	US-5,129,063 A	07-1992	Sainola et al.	710/1
*	C	US-5,608,876 A	03-1997	Cohen et al.	710/300
*	D	US-5,796,964 A	08-1998	Bass et al.	710/305
*	E	US-5,815,647 A	09-1998	Buckland et al.	714/3
*	F	US-5,856,921 A	01-1999	Kim et al.	700/3
*	G	US-5,915,104 A	06-1999	Miller, Steven C.	710/310
*	H	US-5,978,938 A	11-1999	Kaiser et al.	714/48
*	I	US-6,141,718 A	10-2000	Garnett et al.	710/308
*	J	US-6,148,348 A	11-2000	Garnett et al.	710/14
*	K	US-6,341,334 B1	01-2002	Kamemaru, Toshihisa	711/137
*	L	US-2003/0221140 A1	11-2003	Bakke et al.	714/25
*	M	US-2004/0139269 A1	07-2004	Nakamura, Yuji	710/310

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/716,913	Applicant(s)/Patent Under Reexamination FLETCHER ET AL.	
	Examiner Jack W. Szeto	Art Unit 2113	Page 3 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,038,644 A	07-1977	Duke et al.	710/107
*	B	US-5,729,767 A	03-1998	Jones et al.	710/62
*	C	US-5,509,127	04-1996	Datwyler et al.	710/311
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.